

1. Introduction

- 1.1 Testing was performed on the LGA 3647 to determine if it meets the requirement of Product Specification , 108-115115 REV.A
- 1.2 Scope

This report covers the electrical, mechanical and environmental performance requirements of the LGA 3647. The qualification testing for standard type was performed between 6 Sep 2016 and 14 Oct 2016.

1.3 Conclusion

LGA 3647 meets the electrical, mechanical and environmental performance requirements of Product Specification, 108-115115 REV.A

1.4 Test Samples

Samples were taken randomly from current production. The following samples were used.

Part Number	Description
2-2129710-5	LGA 3647-0 left segment (individual package)
2-2129710-6	LGA 3647-0 right segment (individual package)
2-2129710-7	LGA 3647-1 left segment (individual package)
2-2129710-8	LGA 3647-1 right segment (individual package)
2-2822979-3	LGA 3647-0 kit package
2-2822979-4	LGA 3647-1 kit package
2299804-1	Narrow Non-fabric Bolster Plate Assembly
2299805-1	Narrow Back Plate Assembly
2299806-1	Narrow Non-fabric Carrier
2310924-1	Narrow Fabric Bolster Plate Assembly
2310927-1	Narrow Fabric Carrier

Fig. 1



2. Test Contents

No.	Test Items	Requirements	Judgement				
2.1	2.1 Examination of product Visual Inspection No physical damage						
Electrical Requirements							

2.2	2.2 Termination resistance Refer to table 1 (Daisy chain LLCR) (Low level)					
2.3	Dielectric withstanding voltage	360 Vrms, 1 minute Current leakage : 0.5mA Max.	Acceptable			
2.4	Insulation resistance	Impressed voltage 500 VDC. 800MΩ Min.	Acceptable			

	Mechanical Requirements							
2.5	2.5 Durability Test Electric driver (8in-lbf) (Bolster to back plate) Cycles: 6 cycles following a sequence. No thread fastener, galling or shavings as seen from the naked eye							
2.6	Durability Test (Bolster to heatsink)	Electric driver (12in-lbf) Cycles: 6 cycles following a sequence. No thread fastener, galling or shavings as seen from the naked eye	Acceptable					
2.7	2.7 Solder ball share force 600gf Min. Test must be performed on 8 contacts x 3 sockets.							

Figure. 2 (continued)



	Environmental Requirements							
2.8	Durability (Repeated mating / unmating)	Operation speed:8 cycle/min. No. of cycles: 30 cycles Refer to table 1 (Daisy chain LLCR)	Acceptable					
2.9	Vibration, random.	Vibration Frequency: 10 to 2000Hz (Random) Accelerated Velocity: 30.38 m/s ² (3.1G),rms. Vibration Direction: In each of 3 mutually perpendicular planes Duration: 15 minute each Refer to table 1 (Daisy chain LLCR)	Acceptable					
2.10	Physical shock	Accelerated velocity: 490 m/s ² (50 G) Waveform: Halfsine Duration: 11 m sec. Number of drops: 3 drops each to normal and reversed directions of X, Y and Z axes, totally 18 drops. Refer to table 1 (Daisy chain LLCR)	Acceptable					
2.11	Thermal humidity	PHM mated socket with bolster plate & back plate assy and compressive load from PHM 85 °C, 85 % R.H. 504 hour Refer to table 1 (Daisy chain LLCR)	Acceptable					
2.12	Temperature life (Heat aging)	PHM mated socket with bolster plate & back plate assy and compressive load from PHM 105 °C, Duration : 1000 hours Refer to table 1 (Daisy chain LLCR)	Acceptable					
2.13	Thermal cycling	PHM mated socket with bolster plate & back plate assy and compressive load from PHM -25 °C / 15 min., +100 °C / 15 min. (1cycle) No. of cycle : 1250 cycles. Refer to table 1 (Daisy chain LLCR)	Acceptable					
2.14	Resistance to reflow soldering heat	Test socket on PCB. (Lead Free, Sn-Ag-Cu solder ball) Solder ball part Pre-Heat 150~170 °C : 90 sec Min. Heat 217 °C min. : 40~100sec Heat Peak : 245±5 °C Other than solder ball : 260 °C Max No physical damage.	Acceptable					
2.15	Porosity test	EIA-364-60. Test must be performed on 30 loose contacts. 2Pores Max per 30 contacts.	Acceptable					



Maximum daisy chain resistance criterion for different chain length.								
Number of contacts within chain	Maximum LLCR (m-Ohm) allowable at 25degC							
1	165							
2	72							
3	51							
4	43							
5	39							
10	30							
15	28.3							
20	27.7							
50	24.2							
100	23							

Table 1

Chain numbers are subject to change on actual testing



Figure 3 Location of termination resistance daisy chain, socket top side view.



3. Test Sequence

Table 2

Test examination	Test Group								
/ Test sequence	1	2	3	4	5	6	7	8	9
	Test sequence (a)								
Examination of product	1,7	1,5	1,5	1,10	1,5	1,3	1,5	1	1
Termination resistance (Low Level)	2,4,6	2,4	2,4		2,4		2,4		
Dielectric withstanding voltage				2,5,8					
Insulation resistance				3,6,9					
Vibration (Low frequency)	5								
Physical shock	3								
Durability (Repeated mate/unmating)			3 (b)						
Temperature humidity		3(e)		7(g)					
Temperature life (Heat aging)					3(c)				
Thermal cycling				4(f)			3(d)		
Solder ball shear force									2
Resistance to reflow soldering heat						2			
Prosity test								2	

NOTE

(a) Numbers indicate sequence in which the tests are performed.

- (a) Number's indicate sequence in which the tests are performed.
 (b) Durability 30X
 (c) Perform termination resistance 1000 hours.
 (d) Perform termination resistance 300 cycles, 600 cycles, 900cycles, 1250cycles.
- (e) Perform termination resistance 504 hours.

(f) 10 cycles (g) 504 hours



4. Test Result

<u> </u>	Toot Itom		O a stalibli a st	Test Result			Poquiromont	Oraclaster
Group	l est item	N	Condition	Max	Min	Ave	Requirement	Conclusion
	Examination of Product	5	Initial	No	physical dama	age	No abnormalities	Meet Spec
	LLCR	2520	Initial	34.0 mΩ	10.7 mΩ	16.9 mΩ	36mΩ Max	Meet Spec
	Physical Shock	5	Final	No	physical dama	age	No abnormalities	Meet Spec
1	LLCR	2520	Final	35.8 mΩ	10.2 mΩ	16.2 mΩ	36mΩ Max	Meet Spec
	Vibration	5	Final	No	physical dama	age	No abnormalities	Meet Spec
	LLCR	2520	Final	34.7 mΩ	10.0 mΩ	15.6 mΩ	36mΩ Max	Meet Spec
	Examination of Product	5	Final	No	physical dama	age	No abnormalities	Meet Spec
	Examination of Product	5	Initial	No	physical dama	age	No abnormalities	Meet Spec
	LLCR	2520	Initial	26.9 mΩ	11.4 mΩ	16.1 mΩ	36mΩ Max	Meet Spec
2	Temperature Humidity (504H)	5	Final	No	physical dama	age	No abnormalities	Meet Spec
	LLCR	2520	Final	32.5 mΩ	10.0 mΩ	13.4 mΩ	36mΩ Max	Meet Spec
	Examination of Product	5	Final	No	No physical damage		No abnormalities	Meet Spec
	Examination of Product	5	Initial	No	physical dama	age	No abnormalities	Meet Spec
	LLCR	2520	Initial	27.2 mΩ	11.3 mΩ	15.5 mΩ	36mΩ Max	Meet Spec
3	Durability	5	Final	No	physical dama	age	No abnormalities	Meet Spec
	LLCR	2520	Final	24.9 mΩ	10.4 mΩ	13.9 mΩ	36mΩ Max	Meet Spec
	Examination of Product	5	Final	No physical damage			No abnormalities	Meet Spec
	Examination of Product	5	Initial	No physical damage			No abnormalities	Meet Spec
	Withstanding Voltage	25	Initial	No creeping c occurred.	No creeping discharge nor flashover occurred.			Meet Spec
	Insulation Resistance	25	Initial	9.74xE10	9.02xE10	9.42xE10	800M Ω Min	Meet Spec
	Thermal Cycling(10X)	5	Final	No	physical dama	age	No abnormalities	Meet Spec
4	Withstanding Voltage	25	Final	No creeping c occurred.	lischarge nor fla	ashover	No abnormalities	Meet Spec
	Insulation Resistance	25	Final	2.02xE11	0.07xE11	1.17xE11	800M Ω Min	Meet Spec
	Temperature Humidity	5	Final	No	physical dama	age	No abnormalities	Meet Spec
	Withstanding Voltage	25	Final	No creeping c occurred.	lischarge nor fla	ashover	No abnormalities	Meet Spec
	Insulation Resistance	25	Final	4.42xE10	0.34xE10	1.11xE10	800M Ω Min	Meet Spec
	Examination of Product	5	Final	No	physical dama	age	No abnormalities	Meet Spec
	Examination of Product	5	Initial	No	physical dama	age	No abnormalities	Meet Spec
	LLCR	2520	Initial	28.1 mΩ	11.7 mΩ	16.1 mΩ	36mΩ Max	Meet Spec
5	Temperature Life (1000H)	5	Final	No	physical dama	age	No abnormalities	Meet Spec
	LLCR	2520	Final	35.7 mΩ	10.8 mΩ	15.7 mΩ	36mΩ Max	Meet Spec
	Examination of Product	5	Final	No	physical dama	age	No abnormalities	Meet Spec



	T	N	Condition		Test Result	Doguiromont	Ormalian	
Group	l est item	N		Max	Min	Ave	Requirement	Conclusion
	Examination of	5	Initial	N	nhysical dama		No	Meet
	Product	Ŭ	initia		physical dama	lge	abnormalities	Spec
6	Resistance to Reflow	5	Final	No	o physical dama	age	No abnormalities	Meet
	Examination of						No	Meet
	Product	5	Final	No	o physical dama	age	abnormalities	Spec
	Examination of	5	Initial	No	physical dama	age	No	Meet
	Product					5	abnormalities	Spec
	LLCR	2520	Initial	28.1 mΩ	11.7 mΩ	16.1 mΩ	36mΩ Max	Spec
		_	Eine ei	N			No	Meet
	Thermal Cycling(300X)	5	Final	ino physical damage			abnormalities	Spec
		2520	Final	22.7 mO	10.1 mO	16.6 mO	26mO Max	Meet
	LLON	2520	Fillai	32.7 11122			3011122 11/18.2	Spec
	Thermal Cycling(600X)	5	Final	No	No physical damage			Meet
		_			· · · · · · · ·		abnormalities	Spec
7	LLCR	2520	Final	34.5 mΩ	10.2 mΩ	15.4 mΩ	36mΩ Max	Neet
							No	Spec Meet
	Thermal Cycling(900X)	5	Final	No physical damage			abnormalities	Spec
			i .				Meet	
	LLCR	2520	Final	35.5 mΩ	11.5 mΩ	15.6 mΩ	36mΩ Max	Spec
	Thermal Cycling(1250X)	5	Final	N	No physical damage			Meet
		5	i ina	110	physical dama	lge	abnormalities	Spec
	LLCR	2520	Final	34.4 mΩ	11.1 mΩ	17.2 mΩ	36mΩ Max	Meet
	Eveningtion of						Ne	Spec
	Examination of Product	5	Final	No	o physical dama	age	INO abnormalities	Spec
	Examination of						No	Meet
	Product	5	Initial	No	o physical dama	age	abnormalities	Spec
	Devesity Test	-	Final				No	Meet
8	Porosity Test	5	Final	L	ess than 2 pore	es	abnormalities	Spec
	Examination of	5	Final	N	h nhysical dama	200	No	Meet
	Product	5	1 IIIai	INC	physical dama	age	abnormalities	Spec
	Examination of	5	Initial	No	o physical dama	ade	No	Meet
	Product	Ŭ			No prysical damage		abnormalities	Spec
9	Shear Force	24	Final	10.27N	6.70N	8.27N	5.9N Min	Meet
	Examination of						No	Spec
	Product	5	Final	No	No physical damage			Spec

End

REV	REV. RECORD	PREPARED		PREPARED CHECK		APPROVAL	
А	RELEASED	Winng Wang 07 th Dec '1		Simon Li	07 th Dec '16	Corel Wang	07 th Dec '16
В	REVISED	Jeff Wang 12 th Dec '		Simon Li	12 th Dec '16	Corel Wang	12 th Dec '16